



Institut luxembourgeois de la normalisation
de l'accréditation, de la sécurité et qualité
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ILNAS-EN IEC 62228-1:2018

Integrated circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von
Sende-Empfangsgeräten - Teil 1:
Allgemeine Bedingungen und

Circuits intégrés - Évaluation CEM des
émetteurs-récepteurs - Partie 1 :
Conditions générales et définitions

06/2018



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ILNAS-EN IEC 62228-1:2018

EUROPEAN STANDARD **EN IEC 62228-1**

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**Integrated circuits - EMC evaluation of transceivers - Part 1:
General conditions and definitions
(IEC 62228-1:2018)**

Circuits intégrés - Évaluation CEM des émetteurs-
récepteurs - Partie 1 : Conditions générales et définitions
(IEC 62228-1:2018)

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von Sende-
Empfangsgeräten - Teil 1: Allgemeine Bedingungen und
Festlegungen
(IEC 62228-1:2018)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 47A/1018/CDV, future edition 1 of IEC 62228-1, prepared by IEC/SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62228-1:2018.

The following dates are fixed:

- latest date by which the document has to be (dop) 2018-12-01
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2021-06-01
standards conflicting with the
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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-4	2002	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN 61967-4	2002
+ A1	2006		+ A1	2006
-	-		+ corrigendum Dec. 2006	
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity -- Part 3: Non-synchronous transient injection method	EN 62215-3	-
ISO 10605	-	Road vehicles - Test methods for electrical - disturbances from electrostatic discharge		-



INTERNATIONAL STANDARD

Integrated circuits – EMC evaluation of transceivers – Part 1: General conditions and definitions

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